

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	583	250/251.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/20 13:11
L2	1795	250/310.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/20 13:11
L5	0	(ion electron particle) near2 beam and deflect\$6 and detect\$6 and seconday adj (particle electron) and (probe electrode) and control\$6 and voltage	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/20 13:36
L6	0	((ion electron particle) near2 beam and deflect\$6 and detect\$6 and seconday adj (particle electron) and (probe electrode) and control\$6 and voltage).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/20 13:36
L7	170	((ion electron particle) near2 beam and deflect\$6 and detect\$6 and (probe electrode) and control\$6 and voltage).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/20 13:37
L8	79	((ion electron particle) near2 beam and deflect\$6 and detect\$6 and (probe electrode) and control\$6 and voltage and secondary).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/20 13:37
S1	1	"20040155185"	US-PGPUB	OR	ON	2005/07/18 13:57
S2	158	"250"/\$.ccls. and beam and deflect\$6 and detector and secondary adj (particle electron) and (probe electrode) and control\$6 and polarity	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/20 13:35
S3	1	("6774363").PN.	USPAT	OR	OFF	2005/07/19 16:14
S4	1	("5591971").PN.	USPAT	OR	OFF	2005/07/18 14:10
S5	3	"250"/\$.ccls. and beam and deflect\$6 and detector and secondary adj (particle electron) and (probe same conductive) and control\$6 and polarity	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/18 14:13
S6	1300	"250"/\$.ccls. and beam and deflect\$6 and detector and secondary adj (particle electron) and (probe electrode)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/18 14:24
S7	1028	"250"/3\$.ccls. and beam and deflect\$6 and detector and secondary adj (particle electron) and (probe electrode)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/18 14:24

S8	119	S7 and polarity	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/18 14:24
S9	3522	probe and tip and polarity and (sample substrate wafer)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/19 15:52
S10	1198	S9 and beam	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/19 15:52
S11	694	S10 and secondary	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/19 15:52
S12	670	S11 and (voltage potential)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/19 15:54
S13	83	S12 and "250"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/07/19 15:55